

FORM PTO-1449 (Modified)

Docket No. 378-21-011

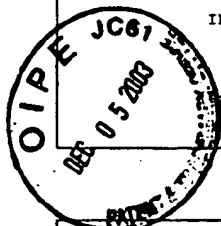
Application Number
10/608,731

INFORMATION DISCLOSURE CITATION
IN AN APPLICATION

Applicants Vincze, et al.

Filing Date 06/27/2003

Group Art Unit 2829



(Use several sheets if necessary)

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number							Date	Name	Class	Subclass	Filing Date If Appropriate
JH	5	7	9	2	9	5	2	08/11/98	Ritchart	73	204.27	05/23/1996
JH	6	5	5	7	4	1	1	05/06/03	Yamada et al.	73	204.26	07/27/2000
JH	6	1	3	1	4	5	3	10/17/00	Sultan et al.	73	204.26	06/29/1998

FOREIGN PATENT DOCUMENTS

	Document Number							Date	Country	Class	Subclass	Translation	
												Yes	No

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner

Jewel K Thompson

Date Considered

8/30/04

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

A circular stamp from the Canadian Intellectual Property Office (CIPO). The text "CIPO" is at the top, "JCS5" is at the top right, and "PATENT & TRADEMARK OFFICE" is at the bottom. The date "OCT 06 2003" is in the center.

U.S. PATENT DOCUMENTS

[illegible]

FOREIGN PATENT DOCUMENTS

[illegible]

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

93	A.	WORKSHOP ON MASS FLOW MEASUREMENT AND CONTROL FOR THE SEMICONDUCTOR INDUSTRY, NATIONAL INST. OF STANDARDS AND TECHNOLOGY, 15-16 MAY 2000, PAGES 1-26
	B.	"HOW TO MONITOR MASS FLOW", PRECISION FLOW DEVICES, INC., CUSTOMER PRESENTATION, 1985. (The year of publication is sufficiently earlier than the effective filing date and any foreign priority date.)
1	C.	CORTE SWERINGEN, "CHOOSING THE BEST FLOWMETER, COLE-PARMER INSTRUMENT CO., REPRINT FROM CHEMICAL ENGINEERING, JULY 1999
	D.	CORTE SWERINGEN, "SELECTING THE RIGHT FLOWMETER-PART 2", COLE-PARMER INSTRUMENT CO REPRINT FROM CHEMICAL ENGINEERING, JAN 2001.
93	E.	"BASICS OF THERMAL MASS FLOW CONTROL", UNIT INSTRUMENTS/KINETICS APPLICATION NOTE, JUNE, 1999.
	F.	"CURVE TRACKING AND POINT MATCHED", VISHAY INTERTECHNOLOGY, INC., DOCUMENT NO. 33005, MAY, 2000.

Examiner <u>Jewel K. Thompson</u>	Date Considered <u>8/30/04</u>
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	Document Number							Date	Country	Class	Subclass	Translation	
												Yes	No

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

	G.	"MASS FLOW CONTROLLER", STBC INC., SALES BROCHURE, 1996. (The year of publication is sufficiently earlier than the effective filing date and any foreign priority date.)
Examiner		Date Considered
		8/30/04
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